

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
F	Add device type 02. Changes to absolute maximum rating and Table I. Editorial changes throughout. Delete vendor CAGE 34333.	93-02-18	M. A. FRYE
G	Make change to high level input current test as specified under Table I. Editorial changes throughout. -ro	00-07-18	R. MONNIN
H	Update drawing to current requirements. -drw	03-01-15	R. MONNIN
J	Make correction to marking paragraph 3.5. -rrp	05-05-11	R. MONNIN
K	Redrawn. Update paragraphs to MIL-PRF-38535 requirements. - drw	17-07-13	Charles F. Saffle
L	Update paragraphs to MIL-PRF-38535 requirements. – jch.	23-01-25	J. Eschmeyer



CURRENT CAGE CODE 67268

THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

Revision Status of Sheets

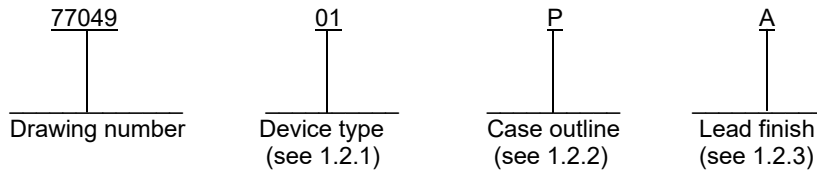
REV	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
SHEET																				
REV	L	L	L	L	L	L	L	L												
SHEET	1	2	3	4	5	6	7	8												

PMIC N/A		PREPARED BY A. J. Foley	<p align="center">DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990 https://www.dla.mil/LandandMaritime</p> <p align="center">MICROCIRCUIT, DIGITAL-LINEAR, TTL DUAL PERIPHERAL DRIVERS, MONOLITHIC SILICON</p>				
<p align="center">STANDARD MICROCIRCUIT DRAWING</p> <p align="center">THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE</p>		CHECKED BY C. R. Jackson					
		APPROVED BY N. A. Hauck					
		DRAWING APPROVAL DATE 77-10-12					
AMSC N/A	REVISION LEVEL L	SIZE A	CAGE CODE 14933	77049			
			SHEET	1 OF 8			

1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	55452	Dual peripheral NAND driver
02	55451	Dual peripheral AND driver

1.2.2 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
P	GDIP1-T8 or CDIP2-T8	8	Dual-in-line
2	CQCC1-N20	20	Square leadless chip carrier

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings.

Supply voltage (VCC)	+7.0 V dc
Input voltage (VIN)	+5.5 V dc
Maximum power dissipation (PD): <u>1/</u>	
Case P	1050 mW
Case 2	1375 mW
Storage temperature range	-65°C to +150°C
Lead temperature (soldering, 10 seconds):	
Case P	+300°C
Case temperature (soldering, 60 seconds):	
Case 2	+260°C
Junction temperature (T _J)	+150°C
Thermal resistance, junction-to-case (θ _{JC})	See MIL-STD-1835
Thermal resistance, junction-to-ambient (θ _{JA}):	
Case P	125°C/W
Case 2	150°C/W

1/ For case P, derate at 8.4mW/°C above TA = +25°C. For case 2, derate at 11.0 mW/°C above TA = +25°C.

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1.4 Recommended operating conditions.

Supply voltage (VCC) +4.5 V dc to +5.5 V dc
Maximum low level input voltage (VIL) 0.8 V dc
Minimum high level input voltage (VIH) 2.0 V dc
Ambient operating temperature range (TA) -55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <https://quicksearch.dla.mil/>.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outline(s). The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth table(s). The truth tables shall be as specified on figure 2.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C unless otherwise specified		Group A subgroups	Device type	Limits		Unit
						Min	Max	
Input clamp voltage	V _{IC}	V _{CC} = 4.5 V, I _{IN} = -12 mA		1	All		-1.5	V
High level output current	I _{OH}	V _{CC} = 4.5 V, V _{IL} = 0.8 V, V _{IH} = 2.0 V, V _{OH} = 30 V		1, 2, 3	All		300	μA
Low level output voltage	V _{OL}	V _{CC} = 4.5 V, V _{IH} = 2 V, V _{IL} = 0.8 V	I _{OL} = 100 mA	1, 2, 3	All		0.5	V
			I _{OL} = 300 mA				0.8	
Input current at maximum input voltage	I _{IN}	V _{CC} = 5.5 V, V _{IN} = 5.5 V		1, 2, 3	All		1.0	mA
High level input current	I _{IH}	V _{CC} = 5.5 V, V _{IN} = 2.4 V		1, 2, 3	All		60	μA
Low level input current	I _{IL}	V _{CC} = 5.5 V, V _{IN} = 0.4 V		1, 2, 3	All		-1.6	mA
Supply current, outputs high	I _{CCH}	V _{CC} = 5.5 V	V _{IN} = 0 V	1, 2, 3	01		14	mA
			V _{IN} = 5 V		02		11	
Supply current, outputs low	I _{CCL}	V _{CC} = 5.5 V	V _{IN} = 0 V	1, 2, 3	01		71	mA
			V _{IN} = 5 V		02		65	
Propagation delay time	t _{PLH} ,	V _{CC} = 5 V, I _O = 200 mA, C _L = 15 pF, R _L = 50 Ω		9	01		35	ns
	t _{PHL}				02		25	
Transition time, low-to-high level output	t _{TLH}	V _{CC} = 5 V, I _O = 200 mA, C _L = 15 pF, R _L = 50 Ω		9	All		8	ns
Transition time, high-to-low level output	t _{THL}	C _L = 15 pF, R _L = 50 Ω		9	All		12	ns
Functional tests		See 4.3.1c		7	All			

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Device types	01 and 02	
Case outlines	P	2
Terminal number	Terminal symbol	
1	1A	NC
2	1B	1A
3	1Y	NC
4	GND	NC
5	2Y	1B
6	2A	NC
7	2B	1Y
8	VCC	NC
9	---	NC
10	---	GND
11	---	NC
12	---	2Y
13	---	NC
14	---	NC
15	---	2A
16	---	NC
17	---	2B
18	---	NC
19	---	NC
20	---	VCC

NC = No connection

FIGURE 1. Terminal connections.

Device type 01

A	B	Y
L	L	H (OFF state)
L	H	H (OFF state)
H	L	H (OFF state)
H	H	L (ON state)

Device type 02

A	B	Y
L	L	L (ON state)
L	H	L (On state)
H	L	L (ON state)
H	H	H (OFF state)

FIGURE 2. Truth tables.

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3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked.

3.5.1 Certification/compliance mark. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DLA Land and Maritime-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DLA Land and Maritime-VA shall be required for any change that affects this drawing.

3.9 Verification and review. DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.

(2) $T_A = +125^{\circ}\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	----
Final electrical test parameters (method 5004)	1*, 2, 3, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 9
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

* PDA applies to subgroup 1.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 8, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 shall include verification of the truth table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

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6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal, or email communication.

6.4 Record of users. Military and industrial users shall inform DLA Land and Maritime when a system application requires configuration control and the applicable SMD to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-8108.

6.5 Comments. Comments on this drawing should be directed to DLA Land and Maritime-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0591.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103 and QML-38535. The vendors listed in MIL-HDBK-103 and QML-38535 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime-VA.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 23-01-25

Approved sources of supply for SMD 77049 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at <https://landandmaritimeapps.dla.mil/programs/smcr/>.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>	Reference military specification PIN
7704901PA	01295	SNJ55452BJG	M38510/12903BPA
	<u>3/</u>	SG55452BY/883B	
77049012A	01295	SNJ55452BFB	
	<u>3/</u>	SG55452BL/883B	
7704902PA	01295	SNJ55451BJG	M38510/12902BPA
	<u>3/</u>	SG55451BY/883B	
77049022A	01295	SNJ55451BFB	
	<u>3/</u>	SG55451BL/883B	

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply.

Vendor CAGE
number

01295

Vendor name
and address

Texas Instruments, Inc.
Semiconductor Group
8505 Forest Ln.
PO Box 660199
Dallas, TX 75243

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